



DCR960G28

Phase Control Thyristor

DS5828-1.2

August 2007

(LN35538)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- High Power Drives
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{RRM} V	Conditions
DCR960G28 DCR960G26 DCR960G24	2800 2600 2400	$\begin{split} T_{vj} = -40^{\circ}\text{C to } 125^{\circ}\text{C}, \\ I_{DRM} = I_{RRM} = 50\text{mA}, \\ V_{DRM}, V_{RRM} t_p = 10\text{ms}, \\ V_{DSM} \& V_{RSM} = \\ V_{DRM} \& V_{RRM} + 100V \\ respectively \end{split}$

Lower voltage grades available.

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR960G28

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

 $\begin{array}{lll} V_{DRM} & 2800V \\ I_{T(AV)} & 960A \\ I_{TSM} & 13000A \\ dV/dt^* & 1500V/\mu s \\ dI/dt & 500A/\mu s \end{array}$

* Higher dV/dt selections available

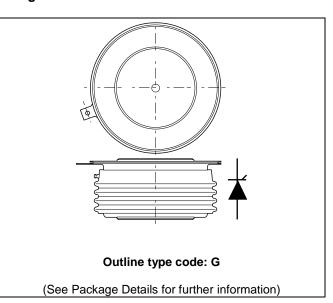


Fig. 1 Package outline

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CURRENT RATINGS

T_{case} = 60°C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Sid	de Cooled			
I _{T(AV)}	Mean on-state current	Half wave resistive load	965	А
I _{T(RMS)}	RMS value	-	1516	А
Ι _Τ	Continuous (direct) on-state current	-	1420	А

SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, T _{case} = 125°C	13.0	kA
l ² t	I ² t for fusing	$V_R = 0$	0.845	MA ² s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled	DC	-	0.0268	°C/W
		Single side cooled	Anode DC	-	0.0527	°C/W
			Cathode DC	-	0.0652	°C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 11.5kN	Double side	-	0.0072	°C/W
		(with mounting compound)	Single side	-	.0144	°C/W
T_{vj}	Virtual junction temperature	Blocking V _{DRM} / _{VRRM}		-	125	°C
T _{stg}	Storage temperature range			-55	125	°C
F _m	Clamping force			10	13	kN

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DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125°C		-	50	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125°C, ga	ate open	-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% V _{DRM} to 2x I _{T(AV)}	Repetitive 50Hz	-	250	A/µs
		Gate source 30V, 10Ω,	Non-repetitive	-	500	A/µs
		$t_r < 0.5 \mu s, T_j = 125$ °C				
$V_{T(TO)}$	Threshold voltage – Low level	100A to 500A at T _{case} = 125°	C	-	0.8	V
	Threshold voltage – High level	500A to 3000A at T _{case} = 125	5°C	-	0.95	V
r _T	On-state slope resistance – Low level	100A to 500A at T _{case} = 125°C		-	0.7556	mΩ
	On-state slope resistance – High level	500A to 3000A at T _{case} = 125°C		-	0.51	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 10Ω		TBD	TBD	μs
		$t_r = 0.5 \mu s, T_j = 25^{\circ}C$				
t _q	Turn-off time	$T_j = 125$ °C, $V_R = 200$ V, $dI/dt = 5$ A/ μ s,		150	350	μs
		dV _{DR} /dt = 20V/µs linear				
Qs	Stored charge	$I_T = 2000A$, $T_j = 125$ °C, $dI/dt = 5A/\mu s$,		700	1500	μC
IL	Latching current	$T_j = 25^{\circ}C, V_D = 5V$		-	3	Α
I _H	Holding current	$T_j = 25^{\circ}\text{C}, R_{G-K} = \infty, I_{TM} = 50^{\circ}$	0A, I _T = 5A	-	300	mA

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GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V_{GT}	Gate trigger voltage	$V_{DRM} = 5V$, $T_{case} = 25$ °C	1.5	V
V_{GD}	Gate non-trigger voltage	At 50% V _{DRM} , T _{case} = 125°C	0.4	V
I _{GT}	Gate trigger current	$V_{DRM} = 5V$, $T_{case} = 25$ °C	250	mA
I _{GD}	Gate non-trigger current	At 50% V _{DRM} , T _{case} = 125°C	10	mA

CURVES

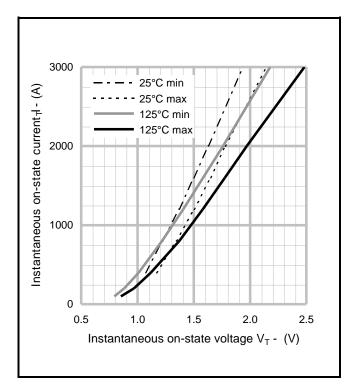


Fig.2 Maximum & minimum on-state characteristics

 $\begin{array}{lll} \textbf{V}_{\text{TM}} \; \textbf{EQUATION} & \text{Where} & A = 0.404415 \\ B = 0.080354 \\ V_{\text{TM}} = A + B \text{ln} \; (I_T) + C.I_T + D. \\ V_{\text{TM}} = A + B \text{ln} \; (I_T) + C.I_T$

these values are valid for $T_j = 125$ °C for $I_T 50$ A to 3000A

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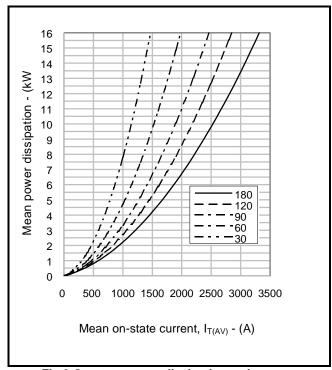


Fig.3 On-state power dissipation - sine wave

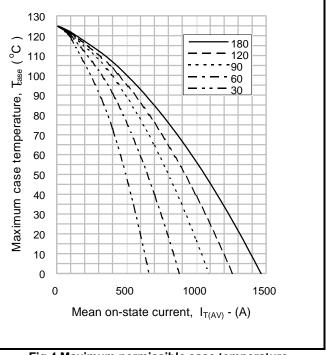


Fig.4 Maximum permissible case temperature, double side cooled – sine wave

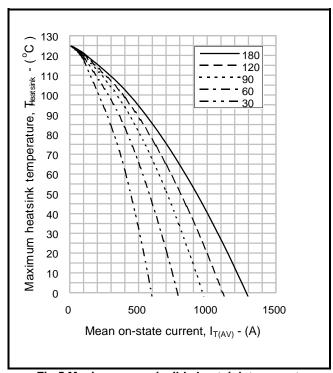


Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

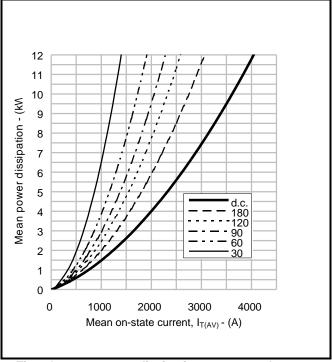


Fig.6 On-state power dissipation - rectangular wave

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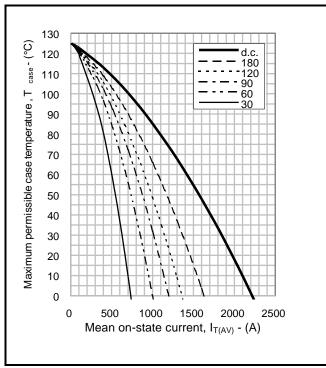


Fig.7 Maximum permissible case temperature, double side cooled – rectangular wave

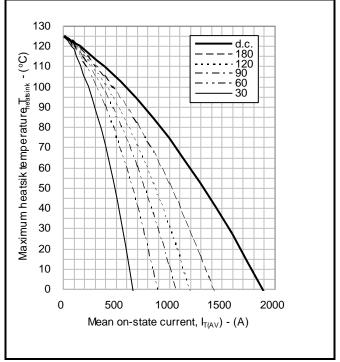
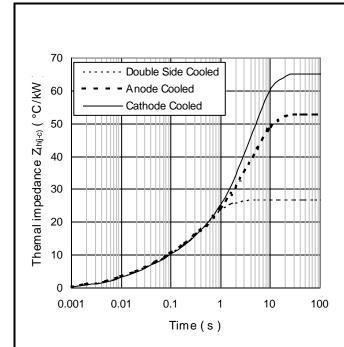


Fig.8 Maximum permissible heatsink temperature, double side cooled – rectangular wave



		1	2	3	4
Double side cooled	R _i (°C/kW)	2.2995	5.4226	16.9074	2.1488
	T _i (s)	0.0066401	0.0457025	0.4962482	1.8248
Anode side cooled	R _i (°C/kW)	2.3214	5.2661	10.2686	34.8031
	T _i (s)	0.0066948	0.045528	0.3484209	4.582
Cathode side cooled	R _i (°C/kW)	2.4895	5.9105	7.4256	49.3432
	T _i (s)	0.0070404	0.052895	0.3933903	4.2295

 $Z_{th} = \sum [R_i x (1-exp. (t/t_i))]$ [1

 $\Delta R_{\text{th(j-c)}}$ Conduction

Tables show the increments of thermal resistance $R_{\text{th(j-c)}}$ when the device operates at conduction angles other than d.c.

Double side cooling			
	ΔZ_{th} (z)		
θ°	sine.	rect.	
180	4.15	2.72	
120	4.90	4.02	
90	5.74	4.79	
60	6.53	5.65	
30	7.16	6.64	
15	7.46	7.18	

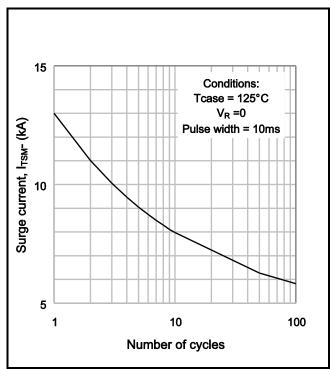
	Anode Side	Cooling	
	$\Delta Z_{th}(z)$		
θ°	sine.	rect.	
180	4.15	2.72	
120	4.89	4.02	
90	5.73	4.78	
60	6.52	5.65	
30	7.15	6.62	
15	7 44	7 16	

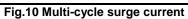
La	tnode Sideo	Cooling	
	ΔZ_{th} (z)		
θ°	sine.	rect.	
180	4.13	2.71	
120	4.87	4.00	
90	5.69	4.76	
60	6.46	5.60	
30	7.07	6.56	
15	7 36	7.00	

Fig.9 Maximum (limit) transient thermal impedance - junction to case (°C/kW)

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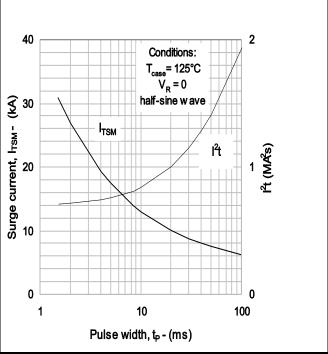


Fig.11 Single-cycle surge current

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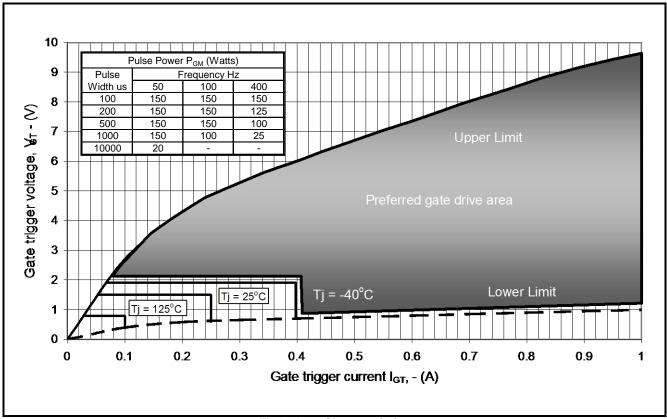


Fig12 Gate Characteristics

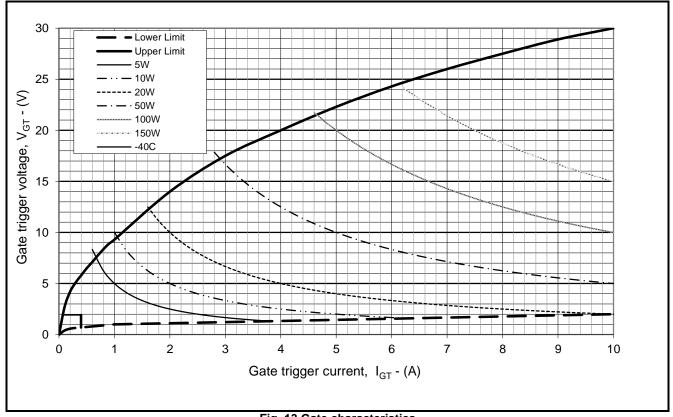


Fig. 13 Gate characteristics

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PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

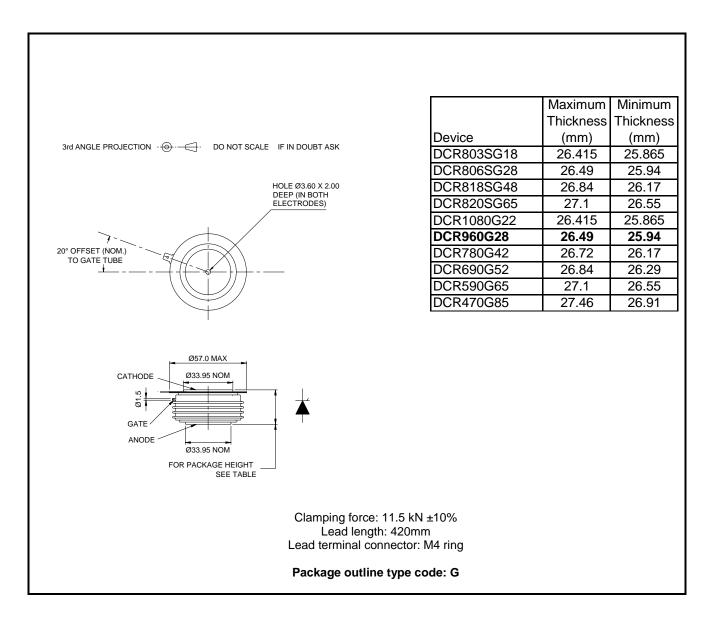


Fig.14 Package outline

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POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



http://www.dynexsemi.com

e-mail: powersolutions@dynexsemi.com

HEADQUARTERS OPERATIONS DYNEX SEMICONDUCTOR LTD Doddington Road, Lincoln

Lincolnshire, LN6 3LF. United Kingdom.

CUSTOMER SERVICE Tel: +44(0)1522 502753 / 502901.

Tel: +44(0)1522 500500

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